

Abstract of the Disclosure:

The memory device contains comparison units with which it is possible to check whether an address applied to the memory device is associated with a memory cell which cannot be

5 properly written to or read out or is located in a memory cell area containing memory cells which cannot be properly written to or read out. During the testing of the memory device, the comparison units can be placed into a state which differs from the state of the comparison units during the normal operation
10 of the memory device.

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